THREEDIMENSIONAL TRACKING USING OBJECT DEFOCUS In Twodimensional Scanning Electron Microscope Images

Christian Dahmen

Division Microrobotics and Control Engineering, University of Oldenburg, Oldenburg, Germany

Keywords: Image processing, Object tracking, Depth estimation, Focus analysis.

Abstract: This paper proposes a tracking algorithm for the extraction of threedimensional position data from SEM images. An algorithm based on active contours with region-based minimization is chosen as basis for twodimensional tracking. This algorithm is then augmented by the incorporation of defocus analysis to estimate the out-of-focus displacement of the object. To solve the ambiguity of the out-of-focus displacement, the astigmatism of the SEM images is used. The separate calculation of variances for the rows and columns of the image enables a successful direction estimation. With the information on the direction, the out-of-focus displacement and the working distance of the acquired image, the distance of the object to the electron gun can be calculated. In combination with the twodimensional part of the tracking, a full threedimensional coordinate set is generated. The approach is tested and evaluated using a positioning setup and the principal feasibility is shown.

1 INTRODUCTION

The SEM has been widely used as a imaging tool for the automated handling of micro- and nanoscale objects (see e.g. (Fatikow, 2007)). While there have been many manipulations executed manually, and with the necessary experience these manipulations have a high success rate, fully automated handling and manipulation of micro- or even nanoscale objects in the SEM still is very rarely encountered. The problems which have to be solved are manifold and not easy to handle. Integrated sensors in the actuators or the setup may deliver some information about the positions of end-effectors and tools, and enable estimates about the position of objects to be manipulated. The real actual position information of objects or tools though is difficult to recover from this data, because of various factors like thermal drift, play or object interactions on the nanoscale. A specific requirement for non-teleoperated processes is therefore the need for sensor feedback generation based on SEM images. The SEM is the only sensor which may deliver an overview over the whole scene, enabling the extraction of the positions of most or all objects engaged in the manipulation. Only the SEM determines these positions in a common coordinate system, which makes it possible to evaluate relative distances between the objects. One problem which is

crucial for the success of any automation approach is the missing information about the position of objects in z-direction, which means orthogonal to the image plane. An example image illustrating the problem is shown in figure 1.



Figure 1: A screenshot showing two objects having different z-positions. One object is a silicon nanowire, the other a deformed STM tip. The distance between the objects in z-direction is not immediately visible.

Dahmen C. (2009). THREEDIMENSIONAL TRACKING USING OBJECT DEFOCUS - In Twodimensional Scanning Electron Microscope Images. In Proceedings of the 6th International Conference on Informatics in Control, Automation and Robotics - Robotics and Automation, pages 72-78 DOI: 10.5220/0002209200720078 Copyright © SciTePress

2 STATE OF THE ART

Different algorithms have been described in the literature extracting the twodimensional position of objects from SEM images for automation purposes. The performance of these algorithms is good, making first simple automation scenarios possible. The approaches used for twodimensional tracking on SEM images and their possible extensions to 3D-tracking will be summarized in the following.

One of the first and most simple approaches used template matching as the basis of the algorithm (Sievers and Fatikow, 2006). A template image is extracted or loaded which contains the object to be tracked. The template image is then cross-correlated with a search area in the input image. The maximum value of the resulting array is in the place where the template is most likely to be found. Due to the use of cross correlation, this approach is very robust against additive noise, which is an advantage especially for fast scanned SEM images. Problems of this approach are that the algorithm is sensitive against certain changes in the object appearance which may occur during handling processes. Examples for these appearance changes are rotation of the object, scaling of the object due to magnification changes and partial occlusion by other objects in the setup. Removing these weaknesses for this method comes with increased computational effort so that a fast enough calculation is not always possible. Extraction of the z-position is not featured and cannot easily be added.

If instead of a template image a CAD model of the object is available, it is possible to use rigid body models to track the object in the SEM image (Kratochvil et al., 2007). The implementation uses measurement lines orthogonal to the model edges and tries to fit the model to visible edges in the image. Model edges which should be invisible are identified and not used for the pose estimation. Though edge detection is difficult in noisy SEM images, the approach yields good results using advanced techniques for discarding or outweighting false edges and through the high number of measurement lines used. When threedimensional CAD-models are used, it is possible to recover the threedimensional pose including in-plane and out-of-plane rotations, except the z-position. The extension for true threedimensional tracking relies on a model of the SEM image projection to yield the zcomponent of the position. This seems to be working for low magnifications.

Another possibility is the use of active contours or snakes (for details about this concept see (Blake and Isard, 2000)), which do not rely on much preexisting knowledge about the object. Active contours are parametrized curves in twodimensional space, that means in the image plane. After coarse initialization the contour is evolving to segment the object from the scene. The contours are coupled with an energy function dependent on their shape or appearance, and on the image data. This energy function is being minimized by moving contour points or the contour as a whole. The part dependent on the contour is called internal energy, the part dependent on the image data is the external energy. In the original formulation, the external energy function was defined to be dependent on the distance of the contour from edges in the image, as explained in (Kass et al., 1988). For the use with noisy SEM images, a region-based approach (see (Sievers, 2006) and (Sievers, 2007)) has shown to be useful. The external energy function here is dependent on the region statistics and the noise characteristics of the imaging source. The goal is to maximize the compound probability of the enclosed region. This approach has proven to be very robust to additive noise, and is inherently robust against scaling and rotation. If the contour minimization is restricted to the euclidean transform space, robustness against partial occlusion is added. Due to the model-free nature of this approach, threedimensional tracking is not immediately possible, but the coupling with focusbased methods is principally possible and shows first promising results in the SEM.

In this paper, the last tracking approach is taken as a basis, and extended to use defocus analysis for depth estimation. The extracted information is only the z-position of the tracked object, without any structural information about the object. For the recovery of threedimensional structure of objects, different methods may be used (see e.g. (Fernandez et al., 2006) or (Jähnisch and Fatikow, 2007)).

3 PRINCIPLE

The principle of the twodimensional tracking has been explained already in (Sievers, 2006). The important aspect is that the active contour algorithm does not only deliver the position information of the object, but at the same time calculates a segmentation of the object from the rest of the scene. This enables further analysis of the enclosed object.

Due to the working principle of the SEM, only a certain range around the set working distance is depicted sharp. Though this range is quite big in comparison to optical microscopes, defocusing is still evident, as can be seen in figure 2. The defocusing in the SEM has been used already in (Eichhorn et al., 2008) to determine the z-position of objects by generating

a sharpness curve over a certain working distance range. One drawback is the amount of time needed to obtain this image sequence and therefore also the disability to monitor dynamic processes. But by analyzing the sharpness of the object which is of interest, it is also possible to directly conclude to the out-offocus displacement of the object, as has been recently demonstrated for the SEM in (Dahmen, 2008).



Figure 2: Comparison of object in focus and out of focus.

The sharpness measure used here is the grey-level variance

$$\sigma^{2}(I, A(C)) = \frac{1}{N_{A(C)}} \sum_{p \in C} I(p) - \bar{I}(A(C))$$
(1)

with

$$\bar{I}(A(C)) = \frac{1}{N_{A(C)}} \sum_{p \in A(C)} I(p)),$$
(2)

and C the contour, A(C) the enclosed area and I the image.

For the object enclosed by the contour this means

$$\sigma^{2}(I(WD), A(C)) = Max \Rightarrow z(Object) = WD \quad (3)$$

with the working distance WD and the z-position of the Object enclosed by the contour z(Object).

One problem which persists after this analysis still is that the out-of-focus displacement turns out to be ambiguous. Two possibilities exist for the solution of this problem, one assuming that the object is nearer than the working distance, the other assuming that the object is further away. This is a situation which is not optimal for automation purposes. Though in some cases the correct solution may be determined by the setup and context knowledge, it is desirable to determine the solution without additional information apart from the image. For this case, a normally undesired effect in SEM imaging may be taken advantage of. During normal use of the SEM, astigmatism is something that is being diminished or removed by astigmatism correction. Astigmatism in the SEM leads to blurry images for the user. An important property of astigmatism is that the sharpness is direction dependent. The focal points are different for two perpendicular directions, as can be seen in figure 3. If we name the two perpendicular directions w_0 and w_1 :



Figure 3: Astigmatism in the SEM, left and right slightly out of focus, middle focused.

To take advantage of this, we calculate additionally to the grey level variance of the image the grey level variance of the rows and columns separately by using

$$\sigma_x^2(I, A(C)) = \sum_y \frac{1}{N_{A(C)}(y)} \sum_{p(x, y) \in C} I(p) - \bar{I}(A(C), y)$$
(5)

with

$$\bar{I}(A(C), y) = \frac{1}{N_{A(C)}(y)} \sum_{p(x, y) \in A(C)} I(p))$$
(6)

and

$$\sigma_{y}^{2}(I,A(C)) = \sum_{x} \frac{1}{N_{A(C)}(x)} \sum_{p(x,y) \in C} I(p) - \bar{I}(A(C),x)$$
(7)

with

$$\bar{I}(A(C), x) = \frac{1}{N_{A(C)}(x)} \sum_{p(x, y) \in A(C)} I(p))$$
(8)

and C the contour, A(C) the enclosed area and I the image.

The two values are normalized to their maximum, which is determined during the initialization phase (see section 4):

$$\hat{\sigma}_y^2(I, A(C)) = \frac{\sigma_y^2(I, A(C))}{\max(\sigma_y^2(I, A(C)))}$$
(9)

and

$$\hat{\sigma}_x^2(I,A(C)) = \frac{\sigma_x^2(I,A(C))}{max(\sigma_x^2(I,A(C)))}$$
(10)

2/- . (~))

In this case we expect a working distance sweep to generate two slightly displaced curves like depicted in figure 4, under the assumption that the object in the image has suitable structure.

With the two curves having slightly displaced maxima, we can estimate from the ratio of the two values

$$r = \frac{\hat{\sigma}_x^2(I, A(C))}{\hat{\sigma}_y^2(I, A(C))}$$
(11)

to which side the out-of-focus displacement occurs.



Figure 4: Expected curves for the different sharpness measures.

4 THE ALGORITHM

The twodimensional base algorithm is similar to the active contour algorithm described in section 2. The principle is depicted in figure 5. Important is that af-



Figure 5: The basic tracking algorithm for the twodimensional part.

ter an initial free minimization, the tracker does only translate and rotate the contour as a whole. This is necessary to enable the out-of-focus estimator to work, because else the enclosed area may change. The same is valid for scaling, which is therefore disabled in the algorithm. In order to enable continuous threedimensional tracking, the algorithm has to be initialized like shown in figure 6. An initial working distance sweep is carried out to acquire the characteristic curve of the tracked object. During this sweep, the twodimensional tracking has to be enabled already. After this, certain calculations and optimizations are carried out on the acquired curves, e.g. it is made sure that the curves are monotonic in sections. After the data has been processed, the tracker can track continuously until either object changes or imaging changes require a reinitialization.



Figure 6: The initialization steps for the threedimensional tracking.

The threedimensional tracking itself consists of the twodimensional tracking algorithm, augmented with a sharpness calculation component, an out-offocus displacement estimator and a direction estimator, like shown in figure 7. The active contour tracker delivers the twodimensional position and the segmentation of the object. This segmentation is then used to mask the original image. From the masked image, the object sharpness is calculated using variance calculation and the directional sharpness measures mentioned in the last section.

The variance value is used to estimate the out-offocus displacement by comparison with the data acquired during initialization.

The directional sharpness values are used to estimate on which sidelobe of the initially acquired sharpness curve the object is in the actual image. After this is known, the information about the displacement value and the displacement direction is combined with the working distance at which the current image was captured. The result is the estimated working distance at which the object is placed. This is then joined with the position information from the twodimensional tracking to generate a complete coordinate set.

5 EXPERIMENTS

For the evaluation of the algorithm, the performance has been tested in a setup inside the SEM. Target object was a chessboard pattern as seen in figure 8. This chessboard pattern has been put on a stub which is mounted to a XYZ positioning setup using piezo slipstick actuated axes with internal position sensors. For the experiment, the internal sensors of the axes were read out and the acquired data joined with the track-



Figure 7: The complete 3D tracking algorithm in the initialized state.

ing data. During the experiment the axes were moved in closed loop mode using the internal sensors. The movement was in a pattern to verify the algorithm performance. All measurements have been executed at a magnification of 800x and a scanspeed of 5 (frame averaging of 2^5 frames) on a LEO scanning electron microscope. The twodimensional pattern of the movement has a size of $21\mu m$ times $39\mu m$. The pattern has been repeated at the z-axis positions of 0.17mm, 0.256mm and 0.32mm.

6 RESULTS

The first result was the generation of the expected curves from figure 4. The result can be seen in figure 9. The shift of the variance calculated in rows and columns separately is clearly visible, which enables the algorithm to work in the anticipated way, estimating the direction of the defocusing.

As can be seen in figure 10, the movement pattern used incorporated movement along each axis as well as in diagonal. Also visible is the distortion of the shape in comparison to the acquired sensor values. The reason for this was determined in additional tests to be a decalibrated sensor of one of the axes. This sensor did not deliver the correct position value, resulting in the closed loop control positioning to a wrong real axis position.

In figure 11 and figure 12 this gets more obvious. While the tracking position in figure 12 closely follows the sensor information, this is not the case in figure 11. Apart from the decalibrated sensor it can be



Figure 8: The structure used for the experiment, a chessboard pattern mounted on a XYZ positioning setup. Visible is the active contour tracking and segmenting one chessboard block.



Figure 9: Measured curves for the variance and the variance calculated in rows and columns separately.

stated that the twodimensional tracking is working.

In order to verify the tracking, the experiment was repeated with a working and calibrated y-axis. The twodimensional tracking can be seen in figure 13. The shape of the movement is correct and the tracking is working and stable.

Figure 14 shows the determined z-Position from the tracking algorithm. Visible is that there is a certain systematic error in the tracked position, as the calculated values deviate from the expected values. The set working distance of the SEM is in the middle of the working distance range shown in figure 14, at the THREEDIMENSIONAL TRACKING USING OBJECT DEFOCUS - In Twodimensional Scanning Electron Microscope Images



Figure 10: Tracked X-Y position of the chessboard pattern. The distorted shape and deviations are due to a decalibrated actuated axis for the y-direction.



Figure 11: The tracked and set y-position over time.



Figure 12: The tracked and set x-position over time.

value 0.28. The problem which occurs here is that the algorithm is most accurate not in the point of maximal focus, but within a certain range on the sidelobes of the sharpness curve. As can be seen in figure 9, the sharpness curve is relatively flat around the maximum. In this interval around the maximum, small changes in detected sharpness, which may also occur due to time variant behavior of the SEM imaging process or due to certain changes in the surrounding setup, will result in large errors in the estimated out-of-focus displacement. This explains also not only the big deviation from the axis set value, but also the large amount of variation during the movement on the



Figure 13: Tracked X-Y position of the chessboard pattern in the repeated measurement.



Figure 14: The tracked z-position over time.

same z-position. So it has to be stated that the optimal working condition for this algorithm is a slightly defocused image.

In figure 15 the tracking result can be seen in three dimensions. The movement pattern is qualitatively visible, though the tracking in z-direction is not as good as in the image plane. Still the goal of the algorithm design has been reached, an estimate has been calculated for the z-position of the object which is principally useable.



Figure 15: The tracked movement in 3D.

7 SUMMARY

In this paper a threedimensional tracking algorithm for the tracking of objects in the SEM has been presented. The algorithm takes advantage of the image defocusing which is evident when objects leave the focal plane. A twodimensional tracking algorithm based on active contours with a region-based minimization has been taken as the base algorithm. Added extensions include the segmentation of the object and the consecutive sharpness calculation. Additionally the variance of the rows and columns is calculated separately for determining the direction of the defocusing. This enables the analysis of the sharpness in different directions. If the image contains astigmatism, it is possible to estimate if the image focal plane lies in front of or behind the object. Experiments have shown that this approach is working and after an initialization phase qualitatively delivers a threedimensional position information. The z-position still contains a systematic error, which is most influential around the best focused point. This error has to be diminished by further analysis and change and optimization of the implementation. Overall the feasibility of this threedimensional tracking algorithm has been shown.

REFERENCES

Blake, A. and Isard, M. (2000). Active Contours. Springer.

- Dahmen, C. (2008). Focus-based depth estimation in the sem. In Proceedings of the International Symposium on Optomechatronic Technologies 2008, volume 7266, page 72661O. SPIE.
- Eichhorn, V., Fatikow, S., Wich, T., Dahmen, C., Sievers, T., Andersen, K., Carlson, K., and Bøggild, P. (2008). Depth-detection methods for microgripper based cnt manipulation in a scanning electron microscope. *Journal of Micro-Nano Mechatronics*. accepted.
- Fatikow, S. (2007). Automated Nanohandling by Microrobots.
- Fernandez, J., Sorzano, C., Marabini, R., and Carazo, J. (2006). Image processing and 3-D reconstruction in electron microscopy. *Signal Processing Magazine*, *IEEE*, 23(3):84–94.
- Jähnisch, M. and Fatikow, S. (2007). 3d vision feedback for nanohandling monitoring in a scanning electron microscope. *International Journal of Optomechatronics*, 1(1):4–26.
- Kass, M., Witkin, A., and Terzopoulos, D. (1988). Snakes: Active contour models. *International Journal of Computer Vision*, 1(4):321–331.
- Kratochvil, B. E., Dong, L. X., and Nelson, B. J. (2007). Real-time rigid-body visual tracking in a scanning electron microscope. In *Proc. of the 7th IEEE Conf.*

on Nanotechnology (IEEE-NANO2007), Hong Kong, China.

- Sievers, T. (2006). Global sensor feedback for automatic nanohandling inside a scanning electron microscope. In Proc. of 2nd I*PROMS NoE Virtual International Conference on Intelligent Production Machines and Systems, pages 289–294.
- Sievers, T. (2007). *Echtzeit-Objektverfolgung im Rasterelektronenmikroskop*. PhD thesis, University of Oldenburg.
- Sievers, T. and Fatikow, S. (2006). Real-time object tracking for the robot-based nanohandling in a scanning electron microscope. *Journal of Micromechatronics*, 3(3-4):267–284.